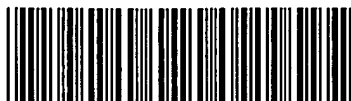


Search Notes

Application/Control No.

10/645,294

Examiner

Benjamin H. Layno

Applicant(s)/Patent under
Reexamination

TANAKA, TOKIO

Art Unit

3711

SEARCHED

Class	Subclass	Date	Examiner
273	292, 302- 306, 308	7/25/2005	BHL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR